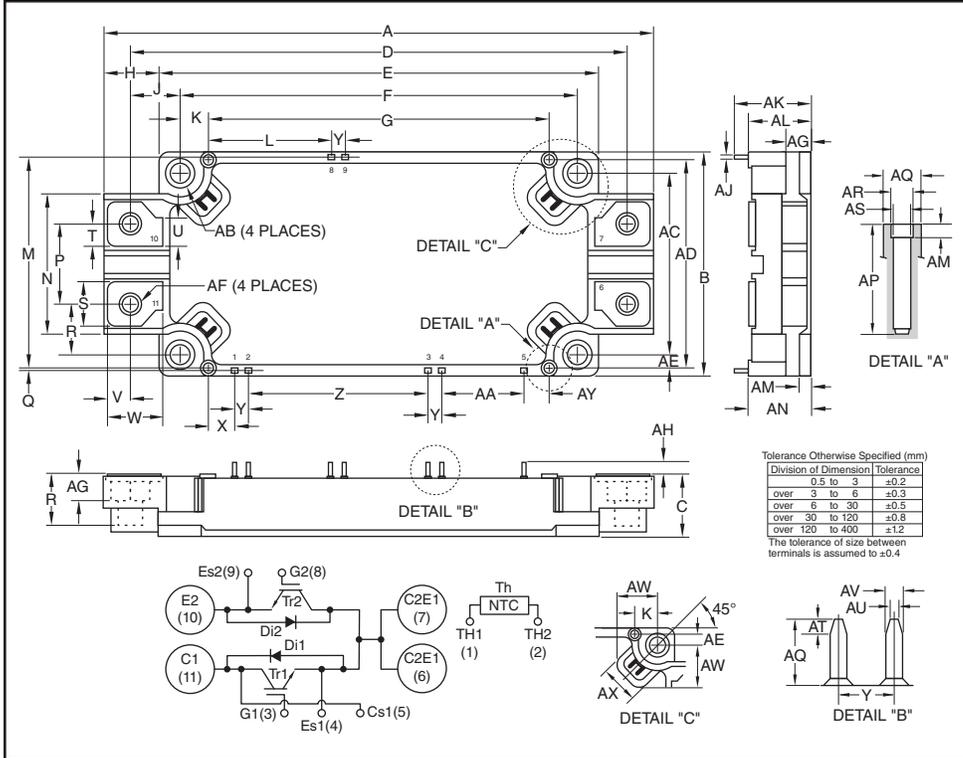


**Dual IGBT  
 NX-Series Module  
 200 Amperes/1700 Volts**



**Description:**

Powerex IGBT Modules are designed for use in switching applications. Each module consists of two IGBT Transistors in a half-bridge configuration with each transistor having a reverse-connected super-fast recovery free-wheel diode. All components and interconnects are isolated from the heat sinking baseplate, offering simplified system assembly and thermal management.

**Features:**

- Low Drive Power
- Low  $V_{CE(sat)}$
- Discrete Super-Fast Recovery Free-Wheel Diode
- Isolated Baseplate for Easy Heat Sinking

**Applications:**

- AC Motor Control
- Motion/Servo Control
- Photovoltaic/Fuel Cell

**Ordering Information:**

Example: Select the complete module number you desire from the table below -i.e. CM200DX-34SA is a 1700V ( $V_{CES}$ ), 200 Ampere Dual IGBT Power Module.

**Outline Drawing and Circuit Diagram**

Dimensions	Inches	Millimeters
A	5.98	152.0
B	2.44	62.0
C	0.67+0.04/-0.02	17.0+1.0/-0.5
D	5.39	137.0
E	4.79	121.7
F	4.33±0.02	110.0±0.5
G	3.72	94.5
H	0.60	15.14
J	0.53	13.5
K	0.31	7.75
L	1.33±0.012	33.91±0.3
M	2.28±0.012	57.95±0.3
N	1.54	39.0
P	0.87	22.0
Q	0.017±0.012	0.45±0.3
R	0.55	14.0
S	0.47	12.0
T	0.24	6.0
U	0.31	8.0
V	0.26	6.5
W	0.62	15.64
X	0.28±0.012	7.24±0.3
Y	0.15	3.81
Z	1.95±0.012	49.53±0.3

Dimensions	Inches	Millimeters
AA	0.9±0.012	22.86±0.3
AB	0.22 Dia.	5.5 Dia.
AC	1.97±0.02	50.0±0.5
AD	2.26	57.5
AE	0.15	3.75
AF	M6	M6
AG	0.28	7.0
AH	0.14	3.5
AJ	0.03	0.8
AK	0.81	20.5
AL	0.70	17.0
AM	0.12	3.0
AN	0.65	16.5
AP	0.49	12.5
AQ	0.18	4.5
AR	0.102 Dia.	2.6 Dia.
AS	0.089 Dia.	2.25 Dia.
AT	0.05	1.2
AU	0.03	0.65
AV	0.05	1.15
AW	0.54	13.7
AX	0.52	13.0
AY	0.285	7.25

Type	Current Rating Amperes	$V_{CES}$ Volts (x 50)
CM	200	34

**CM200DX-34SA**  
**Dual IGBT NX-Series Module**  
 200 Amperes/1700 Volts

**Absolute Maximum Ratings,  $T_j = 25^\circ\text{C}$  unless otherwise specified**

**Inverter Part IGBT/FWDi**

Characteristics	Symbol	Rating	Units
Collector-Emitter Voltage ( $V_{GE} = 0V$ )	$V_{CES}$	1700	Volts
Gate-Emitter Voltage ( $V_{CE} = 0V$ )	$V_{GES}$	$\pm 20$	Volts
Collector Current (DC, $T_C = 125^\circ\text{C}$ )*2,*4	$I_C$	200	Amperes
Collector Current (Pulse, Repetitive)*3	$I_{CRM}$	400	Amperes
Total Power Dissipation ( $T_C = 25^\circ\text{C}$ )*2,*4	$P_{tot}$	2000	Watts
Emitter Current ( $T_C = 25^\circ\text{C}$ )*2,*4	$I_E^{*1}$	200	Amperes
Emitter Current (Pulse, Repetitive)*3	$I_{ERM}^{*1}$	400	Amperes
Maximum Junction Temperature	$T_{j(max)}$	175	$^\circ\text{C}$

**Module**

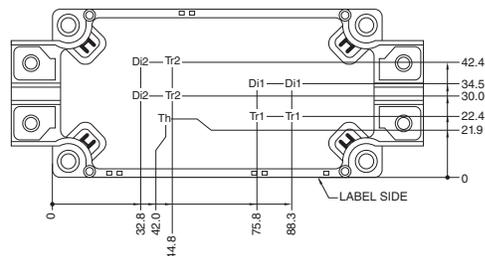
Characteristics	Symbol	Rating	Units
Maximum Case Temperature*2	$T_{C(max)}$	125	$^\circ\text{C}$
Operating Junction Temperature	$T_{j(op)}$	-40 to +150	$^\circ\text{C}$
Storage Temperature	$T_{stg}$	-40 to +125	$^\circ\text{C}$
Isolation Voltage (Terminals to Baseplate, RMS, $f = 60\text{Hz}$ , AC 1 minute)	$V_{ISO}$	4000	Volts

\*1 Represent ratings and characteristics of the anti-parallel, emitter-to-collector free wheeling diode (FWDi).

\*2 Case temperature ( $T_C$ ) and heatsink temperature ( $T_s$ ) is measured on the surface (mounting side) of the baseplate and the heatsink side just under the chips. Refer to the figure to the right for chip location.

The heatsink thermal resistance should be measured just under the chips.  
 \*3 Pulse width and repetition rate should be such that device junction temperature ( $T_j$ ) does not exceed  $T_{j(max)}$  rating.

\*4 Junction temperature ( $T_j$ ) should not increase beyond maximum junction temperature ( $T_{j(max)}$ ) rating.



Tr1, Tr2: IGBT, Di1, Di2: FWDi, Th: NTC Thermistor  
 Each mark points to the center position of each chip.

**CM200DX-34SA**  
**Dual IGBT NX-Series Module**  
 200 Amperes/1700 Volts

**Electrical Characteristics,  $T_j = 25^\circ\text{C}$  unless otherwise specified**

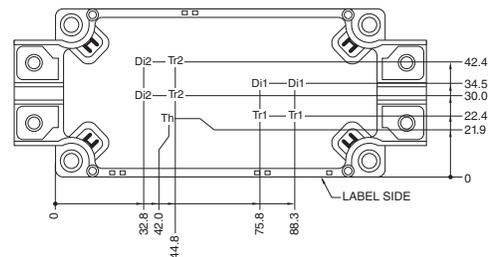
**Inverter Part IGBT/FWDI**

Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Collector-Emitter Cutoff Current	$I_{CES}$	$V_{CE} = V_{CES}, V_{GE} = 0V$	—	—	1	mA
Gate-Emitter Leakage Current	$I_{GES}$	$V_{GE} = V_{GES}, V_{CE} = 0V$	—	—	0.5	$\mu\text{A}$
Gate-Emitter Threshold Voltage	$V_{GE(th)}$	$I_C = 20\text{mA}, V_{CE} = 10V$	5.4	6	6.6	Volts
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$ (Terminal)	$I_C = 200\text{A}, V_{GE} = 15V, T_j = 25^\circ\text{C}^*6$	—	2.0	2.5	Volts
		$I_C = 200\text{A}, V_{GE} = 15V, T_j = 125^\circ\text{C}^*6$	—	2.2	—	Volts
		$I_C = 200\text{A}, V_{GE} = 15V, T_j = 150^\circ\text{C}^*6$	—	2.25	—	Volts
Collector-Emitter Saturation Voltage	$V_{CE(sat)}$ (Chip)	$I_C = 200\text{A}, V_{GE} = 15V, T_j = 25^\circ\text{C}^*6$	—	1.9	2.4	Volts
		$I_C = 200\text{A}, V_{GE} = 15V, T_j = 125^\circ\text{C}^*6$	—	2.1	—	Volts
		$I_C = 200\text{A}, V_{GE} = 15V, T_j = 150^\circ\text{C}^*6$	—	2.15	—	Volts
Input Capacitance	$C_{ies}$		—	—	35	nF
Output Capacitance	$C_{oes}$	$V_{CE} = 10V, V_{GE} = 0V$	—	—	1.5	nF
Reverse Transfer Capacitance	$C_{res}$		—	—	0.35	nF
Gate Charge	$Q_G$	$V_{CC} = 1000V, I_C = 200\text{A}, V_{GE} = 15V$	—	1100	—	nC
Turn-on Delay Time	$t_{d(on)}$		—	—	400	ns
Rise Time	$t_r$	$V_{CC} = 1000V, I_C = 200\text{A}, V_{GE} = \pm 15V,$	—	—	100	ns
Turn-off Delay Time	$t_{d(off)}$	$R_G = 0\Omega, \text{ Inductive Load}$	—	—	700	ns
Fall Time	$t_f$		—	—	600	ns
Emitter-Collector Voltage	$V_{EC}^{*1}$ (Terminal)	$I_E = 200\text{A}, V_{GE} = 0V, T_j = 25^\circ\text{C}^*6$	—	4.1	5.3	Volts
		$I_E = 200\text{A}, V_{GE} = 0V, T_j = 125^\circ\text{C}^*6$	—	2.9	—	Volts
		$I_E = 200\text{A}, V_{GE} = 0V, T_j = 150^\circ\text{C}^*6$	—	2.7	—	Volts
Emitter-Collector Voltage	$V_{EC}^{*1}$ (Chip)	$I_E = 200\text{A}, V_{GE} = 0V, T_j = 25^\circ\text{C}^*6$	—	4.0	5.2	Volts
		$I_E = 200\text{A}, V_{GE} = 0V, T_j = 125^\circ\text{C}^*6$	—	2.8	—	Volts
		$I_E = 200\text{A}, V_{GE} = 0V, T_j = 150^\circ\text{C}^*6$	—	2.6	—	Volts
Reverse Recovery Time	$t_{rr}^{*1}$	$V_{CC} = 1000V, I_E = 200\text{A}, V_{GE} = \pm 15V$	—	—	300	ns
Reverse Recovery Charge	$Q_{rr}^{*1}$	$R_G = 0\Omega, \text{ Inductive Load}$	—	8.0	—	$\mu\text{C}$
Turn-on Switching Energy per Pulse	$E_{on}$	$V_{CC} = 1000V, I_C = I_E = 200\text{A},$	—	28	—	mJ
Turn-off Switching Energy per Pulse	$E_{off}$	$V_{GE} = \pm 15V, R_G = 0\Omega,$	—	52	—	mJ
Reverse Recovery Energy per Pulse	$E_{rr}^{*1}$	$T_j = 150^\circ\text{C}, \text{ Inductive Load}$	—	42	—	mJ
Internal Lead Resistance	$R_{CC}^{*2} + EE^{*2}$	Main Terminals-Chip, Per Switch, $T_C = 25^\circ\text{C}^*2$	—	—	2.0	m $\Omega$
Internal Gate Resistance	$r_g$	Per Switch	—	2.5	—	$\Omega$

\*1 Represent ratings and characteristics of the anti-parallel, emitter-to-collector free wheeling diode (FWDI).

\*2 Case temperature ( $T_C$ ) and heatsink temperature ( $T_S$ ) is measured on the surface (mounting side) of the baseplate and the heatsink side just under the chips. Refer to the figure to the right for chip location. The heatsink thermal resistance should be measured just under the chips.

\*6 Pulse width and repetition rate should be such as to cause negligible temperature rise.



T1, T2: IGBT, D1, D2: FWDI, Th: NTC Thermistor  
 Each mark points to the center position of each chip.

**CM200DX-34SA**  
**Dual IGBT NX-Series Module**  
 200 Amperes/1700 Volts

**Electrical Characteristics,  $T_j = 25^\circ\text{C}$  unless otherwise specified (continued)**

**NTC Thermistor Part**

Characteristics	Symbol	Test Conditions	Min.	Typ.	Max.	Units
Zero Power Resistance	$R_{25}$	$T_C = 25^\circ\text{C}^{*2}$	4.85	5.00	5.15	k $\Omega$
Deviation of Resistance	$\Delta R/R$	$T_C = 100^\circ\text{C}$ , $R_{100} = 493\Omega$	-7.3	—	+7.8	%
B Constant	$B_{(25/50)}$	Approximate by Equation <sup>*7</sup>	—	3375	—	K
Power Dissipation	$P_{25}$	$T_C = 25^\circ\text{C}^{*2}$	—	—	10	mW

**Thermal Resistance Characteristics**

Thermal Resistance, Junction to Case <sup>*2</sup>	$R_{th(j-c)Q}$	Per Inverter IGBT	—	—	0.075	K/W
Thermal Resistance, Junction to Case <sup>*2</sup>	$R_{th(j-c)D}$	Per Inverter FWDi	—	—	0.12	K/W
Contact Thermal Resistance, Case to Heatsink <sup>*2</sup>	$R_{th(c-f)}$	Thermal Grease Applied (Per 1 Module) <sup>*8</sup>	—	15	—	K/kW

**Mechanical Characteristics**

Mounting Torque	$M_t$	Mounting to Heatsink, M5 Screw	22	27	31	in-lb
	$M_s$	Mounting to Heatsink, M5 Screw	22	27	31	in-lb
Creepage Distance	$d_s$	Terminal to Terminal	17.0	—	—	mm
		Terminal to Baseplate	16.8	—	—	mm
Clearance	$d_a$	Terminal to Terminal	10.0	—	—	mm
		Terminal to Baseplate	10.0	—	—	mm
Weight	m		—	350	—	Grams
Flatness of Baseplate	$e_c$	On Centerline X, Y <sup>*5</sup>	$\pm 0$	—	+100	$\mu\text{m}$

**Recommended Operating Conditions,  $T_a = 25^\circ\text{C}$**

(DC) Supply Voltage	$V_{CC}$	Applied Across C1-E2	—	1000	1200	Volts
Gate (-Emitter Drive) Voltage	$V_{GE(on)}$	Applied Across G1-Es1 / G2-Es2	13.5	15.0	16.5	Volts
External Gate Resistance	$R_G$	Per Switch	0	—	35	$\Omega$

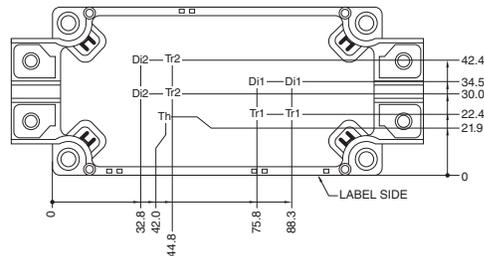
<sup>\*2</sup> Case temperature ( $T_C$ ) and heatsink temperature ( $T_s$ ) is measured on the surface (mounting side) of the baseplate and the heatsink side just under the chips. Refer to the figure to the right for chip location. The heatsink thermal resistance should be measured just under the chips.

<sup>\*5</sup> Baseplate (mounting side) flatness measurement points (X, Y) are shown in the figure below.

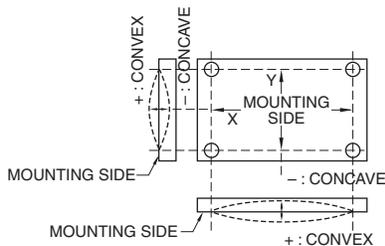
$$^{*7} B_{(25/50)} = \ln\left(\frac{R_{25}}{R_{50}}\right) / \left(\frac{1}{T_{25}} - \frac{1}{T_{50}}\right)$$

$R_{25}$ ; Resistance at Absolute Temperature  $T_{25}$  [K];  $T_{25} = 25 [^\circ\text{C}] + 273.15 = 298.15$  [K]  
 $R_{50}$ ; Resistance at Absolute Temperature  $T_{50}$  [K];  $T_{50} = 50 [^\circ\text{C}] + 273.15 = 323.15$  [K]

<sup>\*8</sup> Typical value is measured by using thermally conductive grease of  $\lambda = 0.9$  [W/(m • K)].

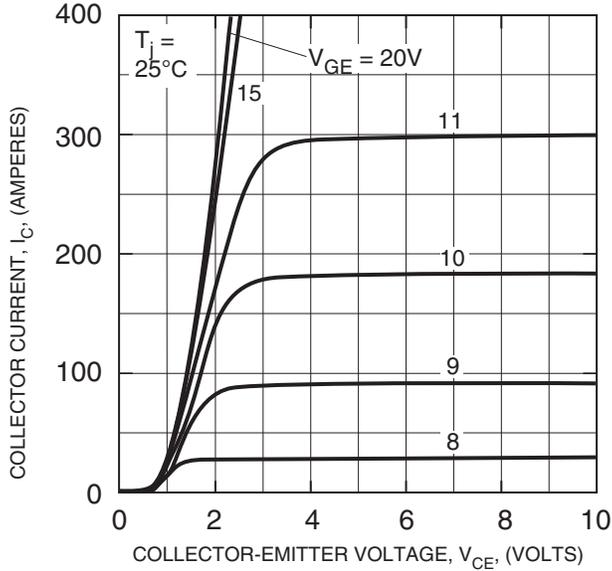


Tr1, Tr2: IGBT, Di1, Di2: FWDI, Th: NTC Thermistor  
 Each mark points to the center position of each chip.

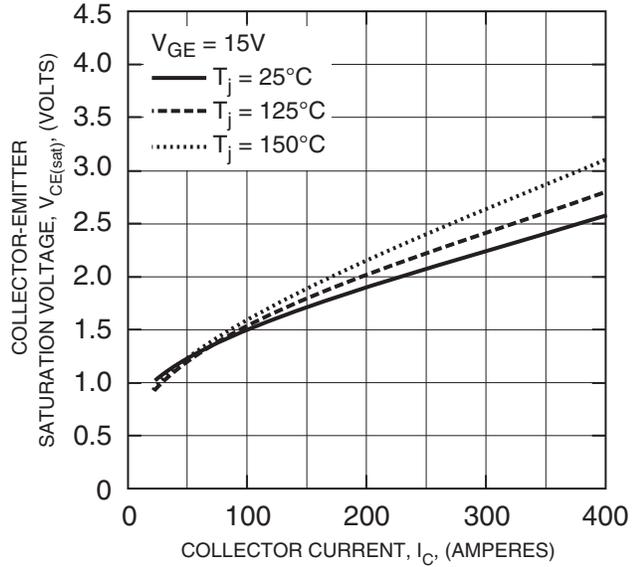


**CM200DX-34SA**  
**Dual IGBT NX-Series Module**  
 200 Amperes/1700 Volts

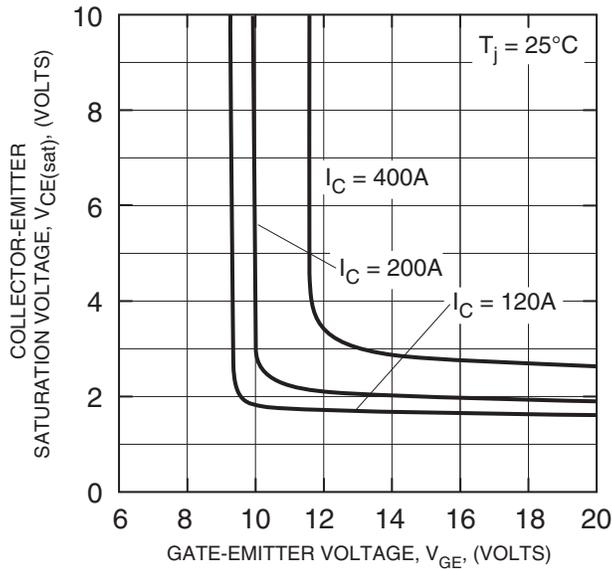
**OUTPUT CHARACTERISTICS  
(CHIP - TYPICAL)**



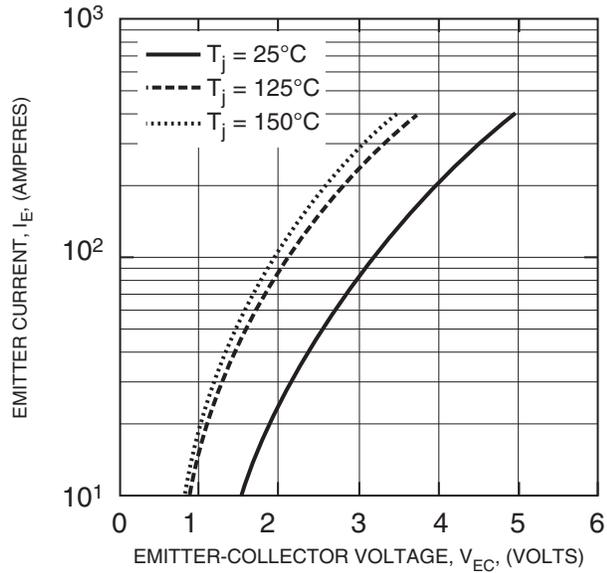
**COLLECTOR-EMITTER  
SATURATION VOLTAGE CHARACTERISTICS  
(CHIP - TYPICAL)**



**COLLECTOR-EMITTER  
SATURATION VOLTAGE CHARACTERISTICS  
(CHIP - TYPICAL)**

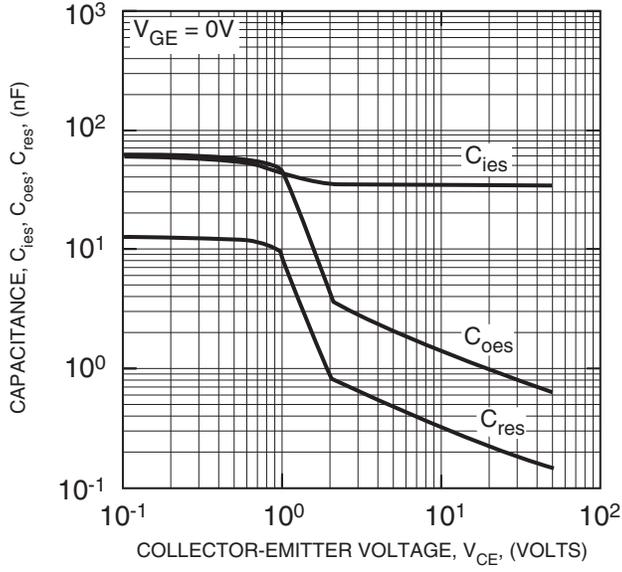


**FREE-WHEEL DIODE  
FORWARD CHARACTERISTICS  
(CHIP - TYPICAL)**

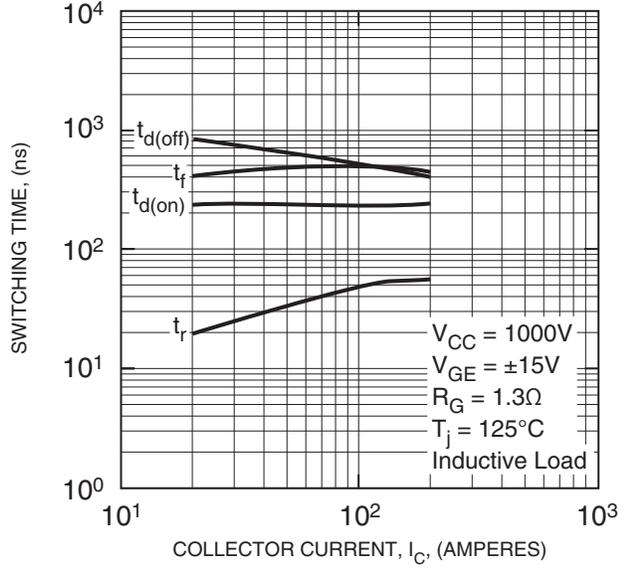


**CM200DX-34SA**  
**Dual IGBT NX-Series Module**  
 200 Amperes/1700 Volts

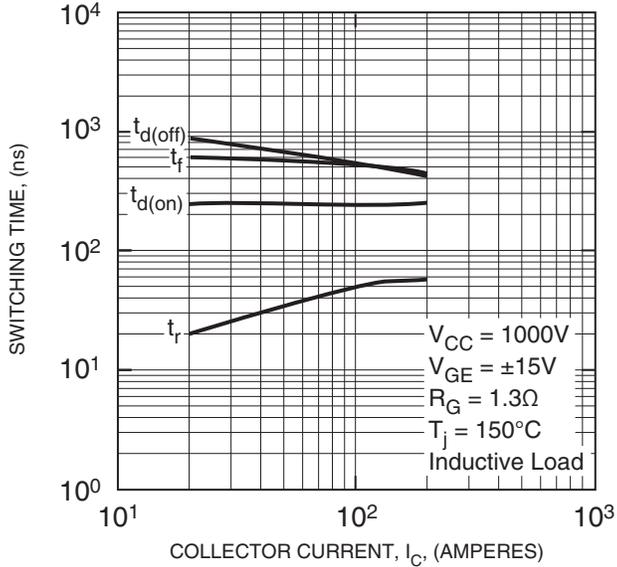
**CAPACITANCE VS.  $V_{CE}$**   
**(TYPICAL)**



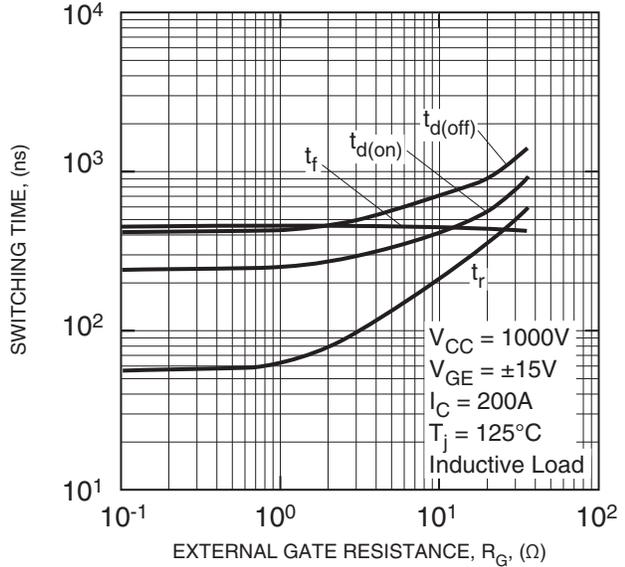
**HALF-BRIDGE**  
**SWITCHING CHARACTERISTICS**  
**(TYPICAL)**



**HALF-BRIDGE**  
**SWITCHING CHARACTERISTICS**  
**(TYPICAL)**

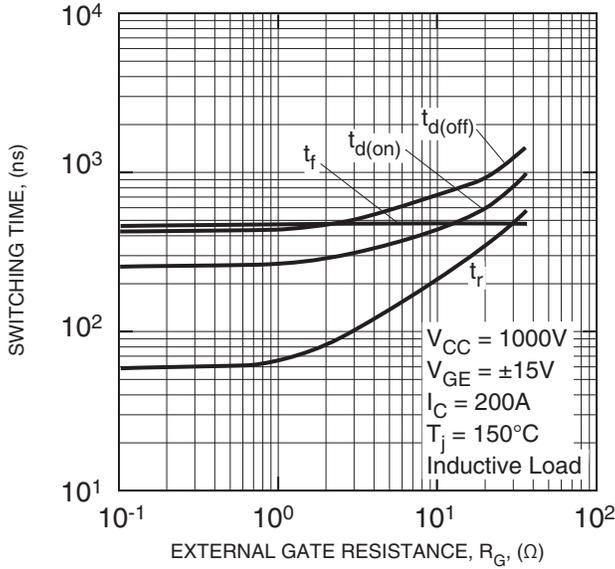


**SWITCHING TIME VS.**  
**GATE RESISTANCE**  
**(TYPICAL)**

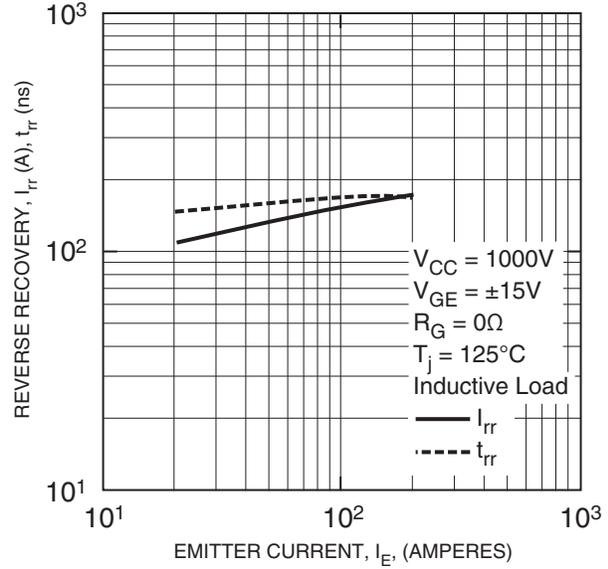


**CM200DX-34SA**  
**Dual IGBT NX-Series Module**  
 200 Amperes/1700 Volts

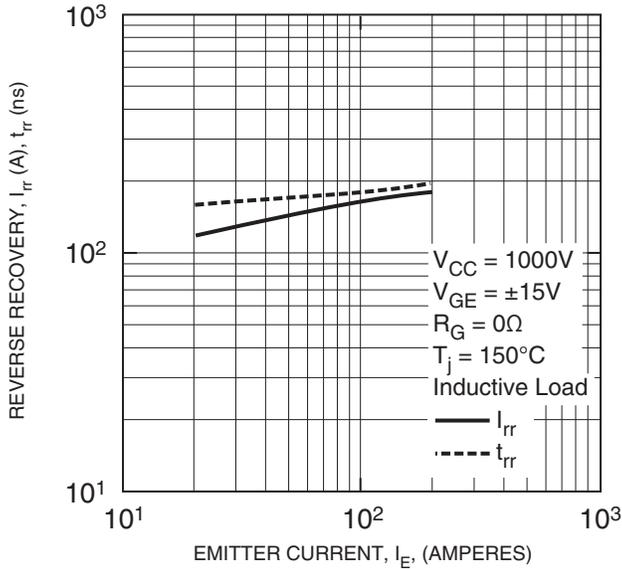
**SWITCHING TIME VS. GATE RESISTANCE (TYPICAL)**



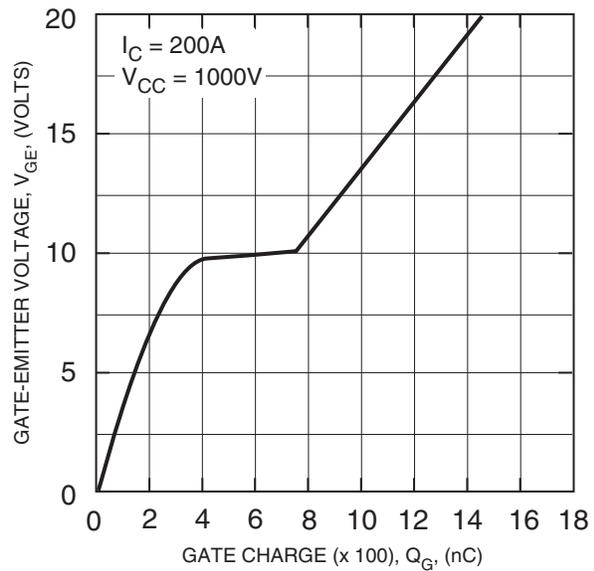
**REVERSE RECOVERY CHARACTERISTICS (TYPICAL)**



**REVERSE RECOVERY CHARACTERISTICS (TYPICAL)**

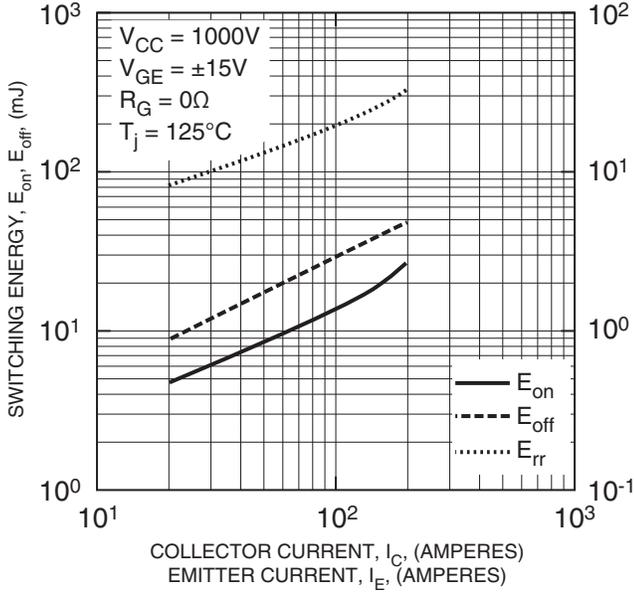


**GATE CHARGE VS.  $V_{GE}$**

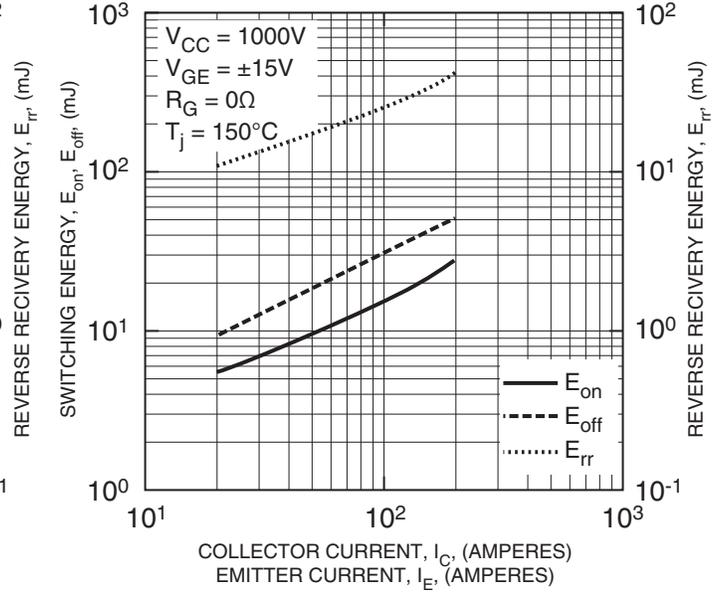


**CM200DX-34SA**  
**Dual IGBT NX-Series Module**  
 200 Amperes/1700 Volts

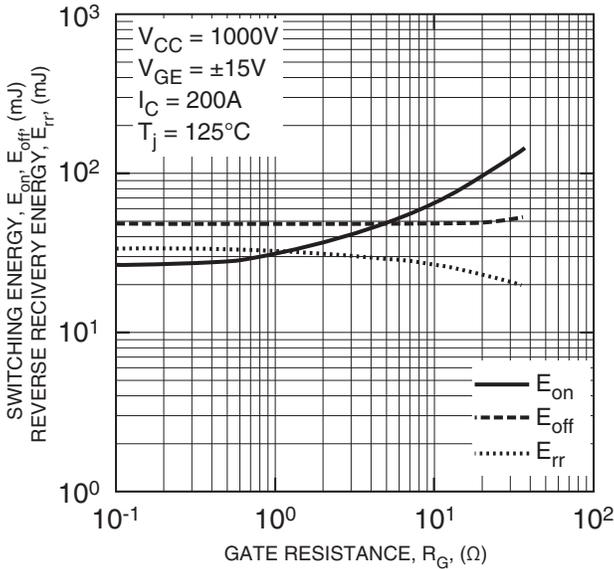
**HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)**



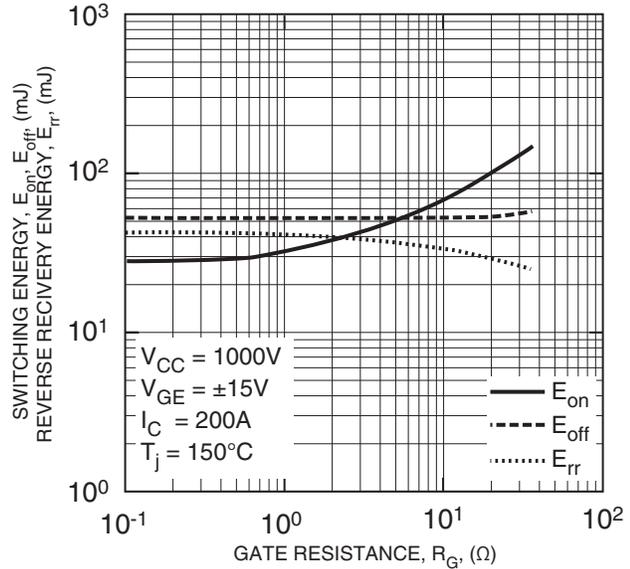
**HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)**



**HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)**



**HALF-BRIDGE SWITCHING CHARACTERISTICS (TYPICAL)**



**CM200DX-34SA**  
**Dual IGBT NX-Series Module**  
 200 Amperes/1700 Volts

